

**Search Notes (continued)**

Application/Control No.

10/617,076

Examiner

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Applicant(s)/Patent under  
Reexamination

TANAKA, GENICHI

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	6	6/13/2006	JSL
716	7	6/13/2006	JSL
716	4	6/13/2006	JSL
716	5	6/13/2006	JSL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
716	6	6/13/2006	JSL
716	7	6/13/2006	JSL
716	4,5	6/13/2006	JSL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	6/13/2006	JSL